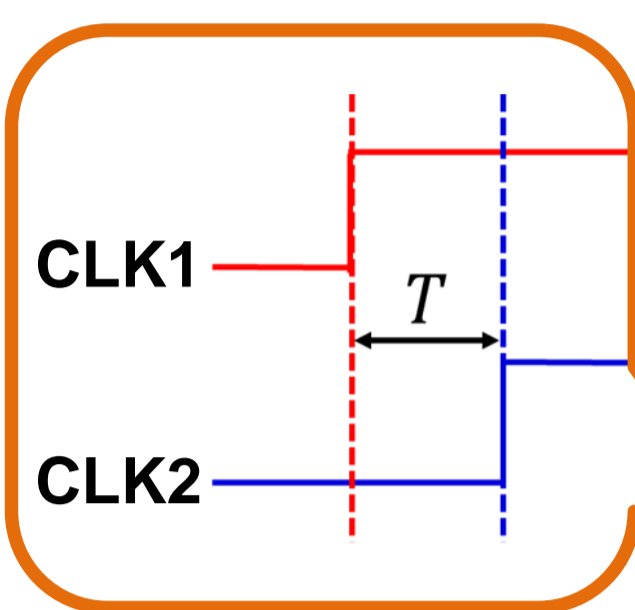
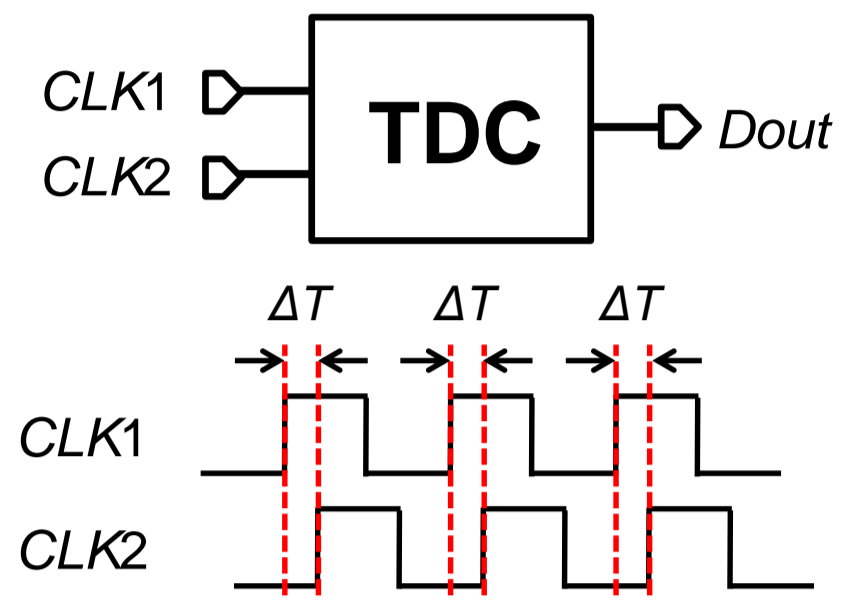


Research Background

Time-to-Digital Converter (TDC)
measures the time and provides digital output



- Can it be measured **more accurately**?
- How can we generate **repetitive signals** of clk 1 and clk 2 with **one shot**?

Research Objective

Development of
highly - linear, fine time-resolution TDC
for high-speed digital I/O interface
timing measurement



Our Innovation

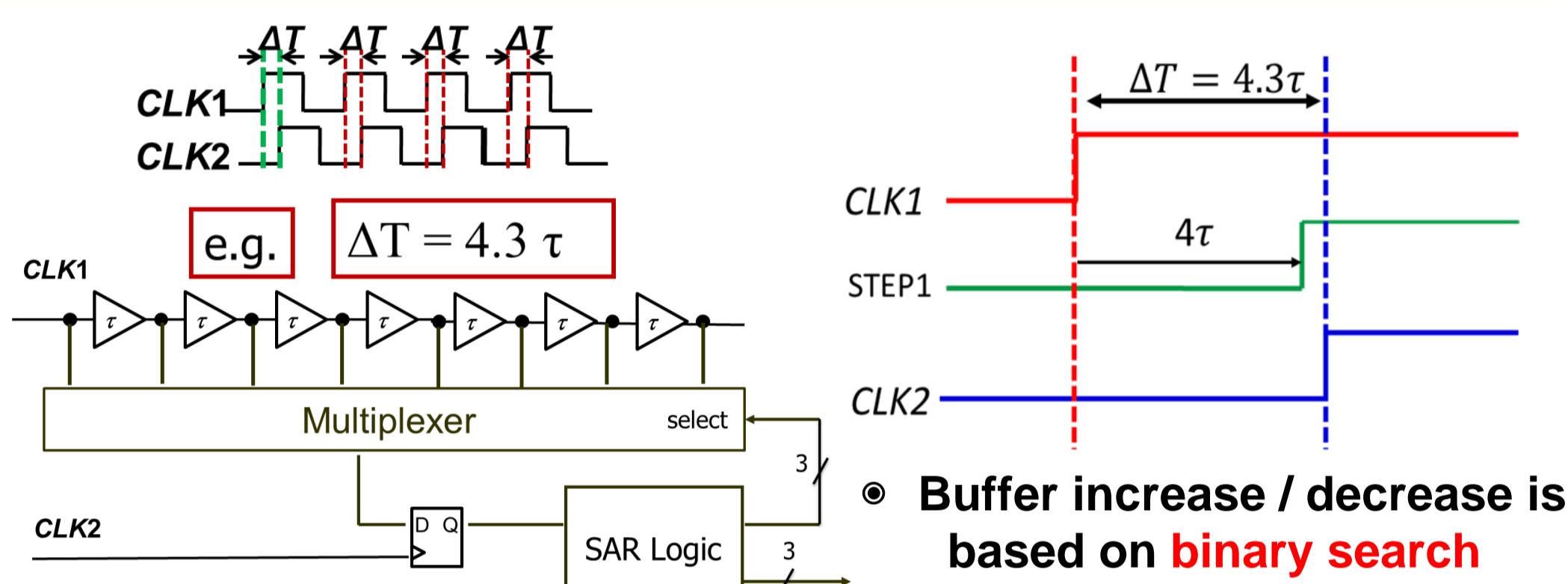
Development of 2 key technologies

for time measurement

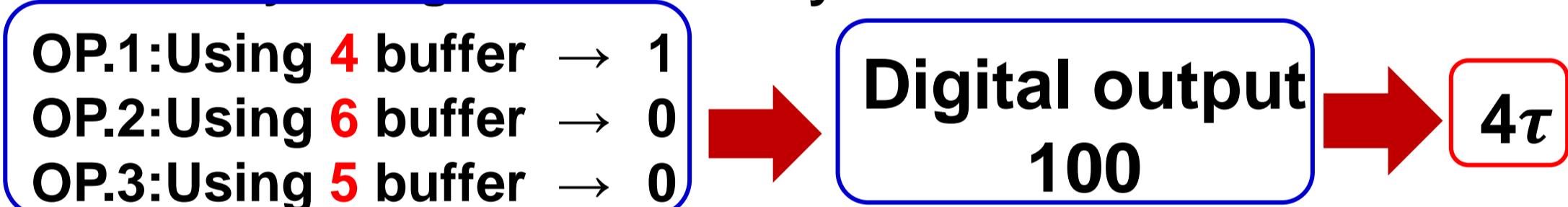
- [I] Two-Step SAR TDC**
→ **Fine time resolution**
- [II] Self-Calibration**
→ **Linear TDC**
- [III] Trigger Circuit**
→ **One-shot timing measurement**

Fine time resolution

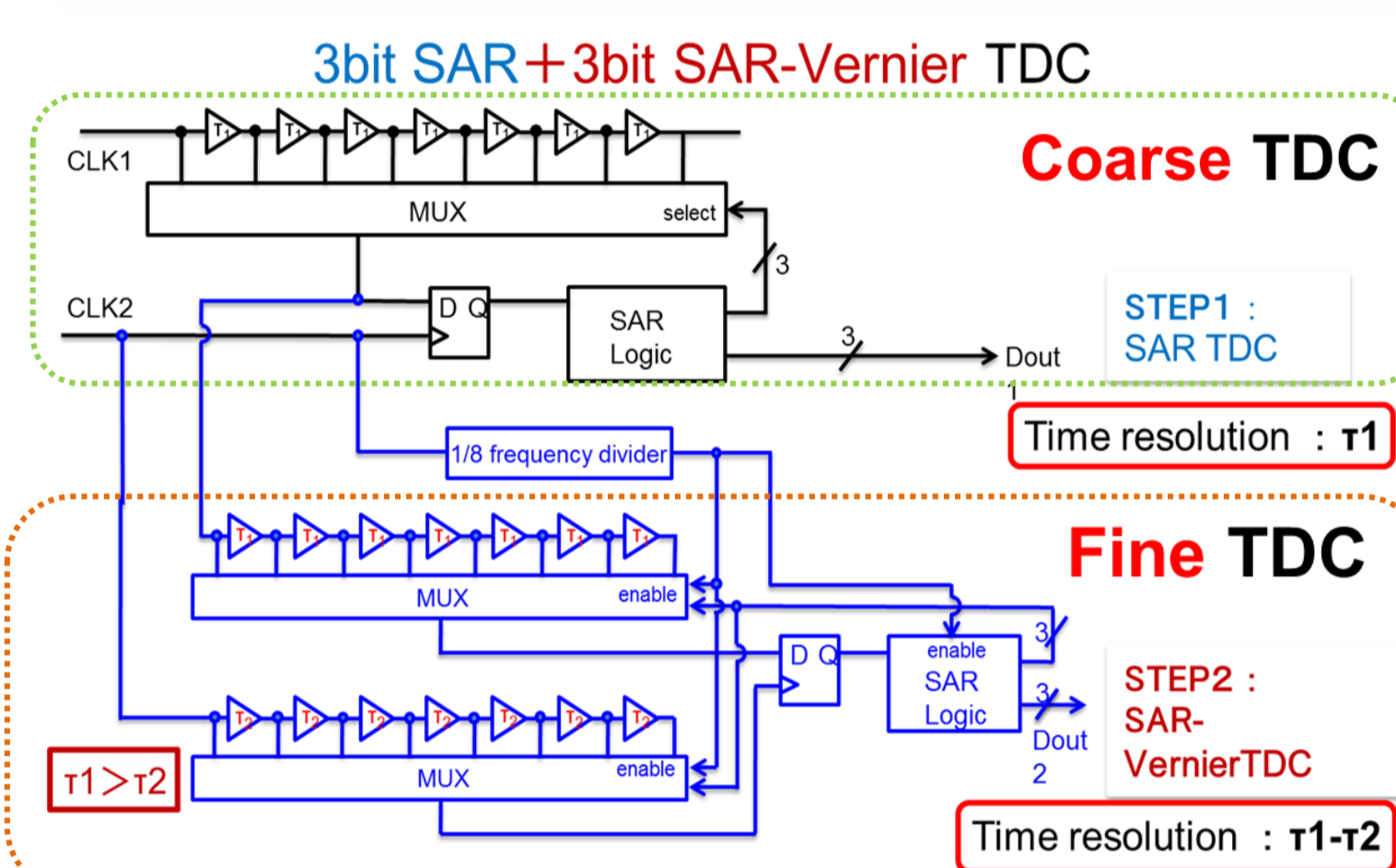
[I] TDC operation



Find the difference between clk 1 and clk 2 by using buffer to delay the clock



Two-Step SAR TDC operation (SAR TDC+Vernier type TDC)

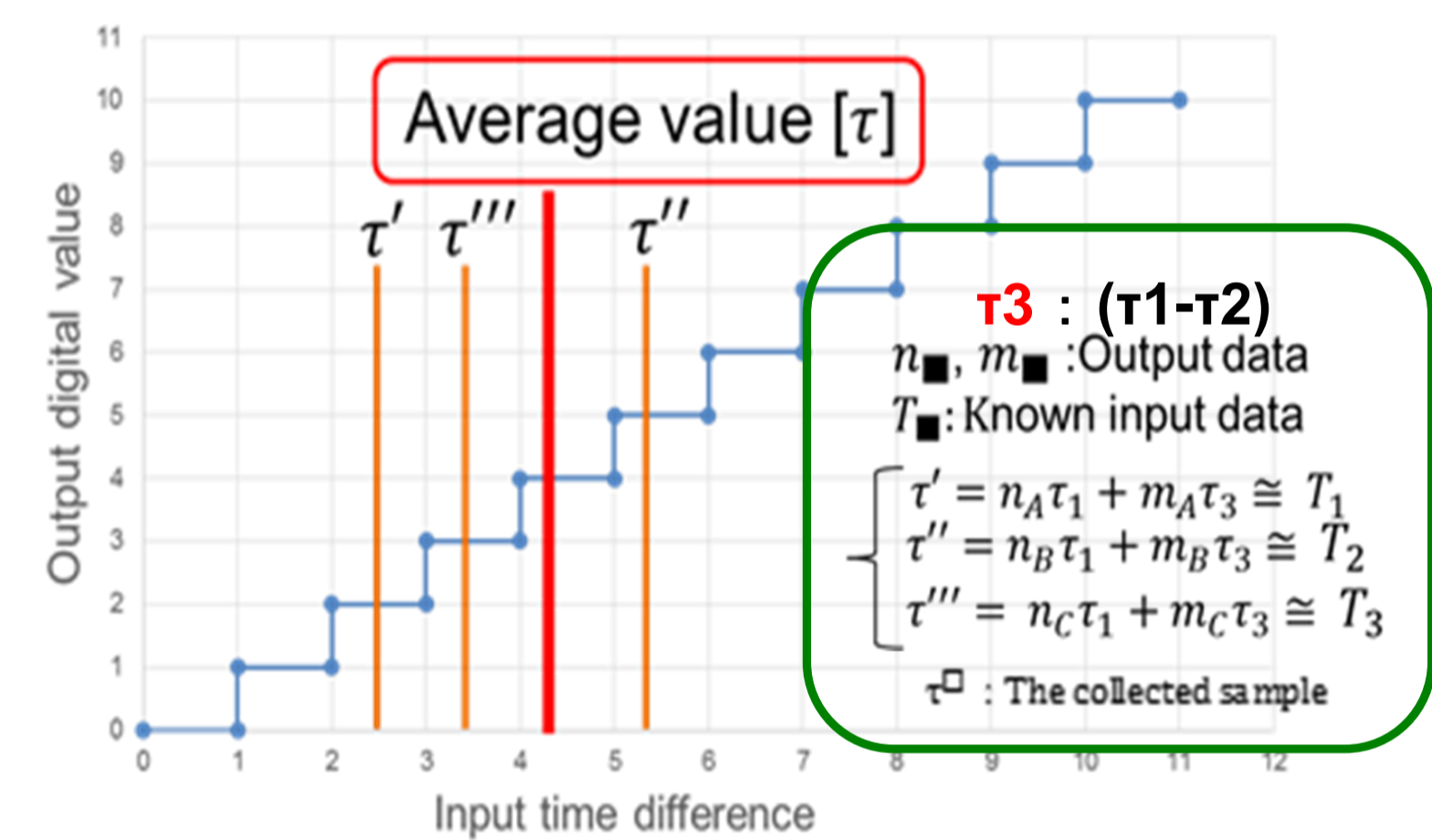


- OP.1: Using **Coarse TDC**(Time resolution τ_1)
- OP.2: Using 1/8 frequency divider
- OP.3: Using **Fine TDC**(Time resolution $\tau_1-\tau_2$)

Linear TDC

[II] Calibration algorithm

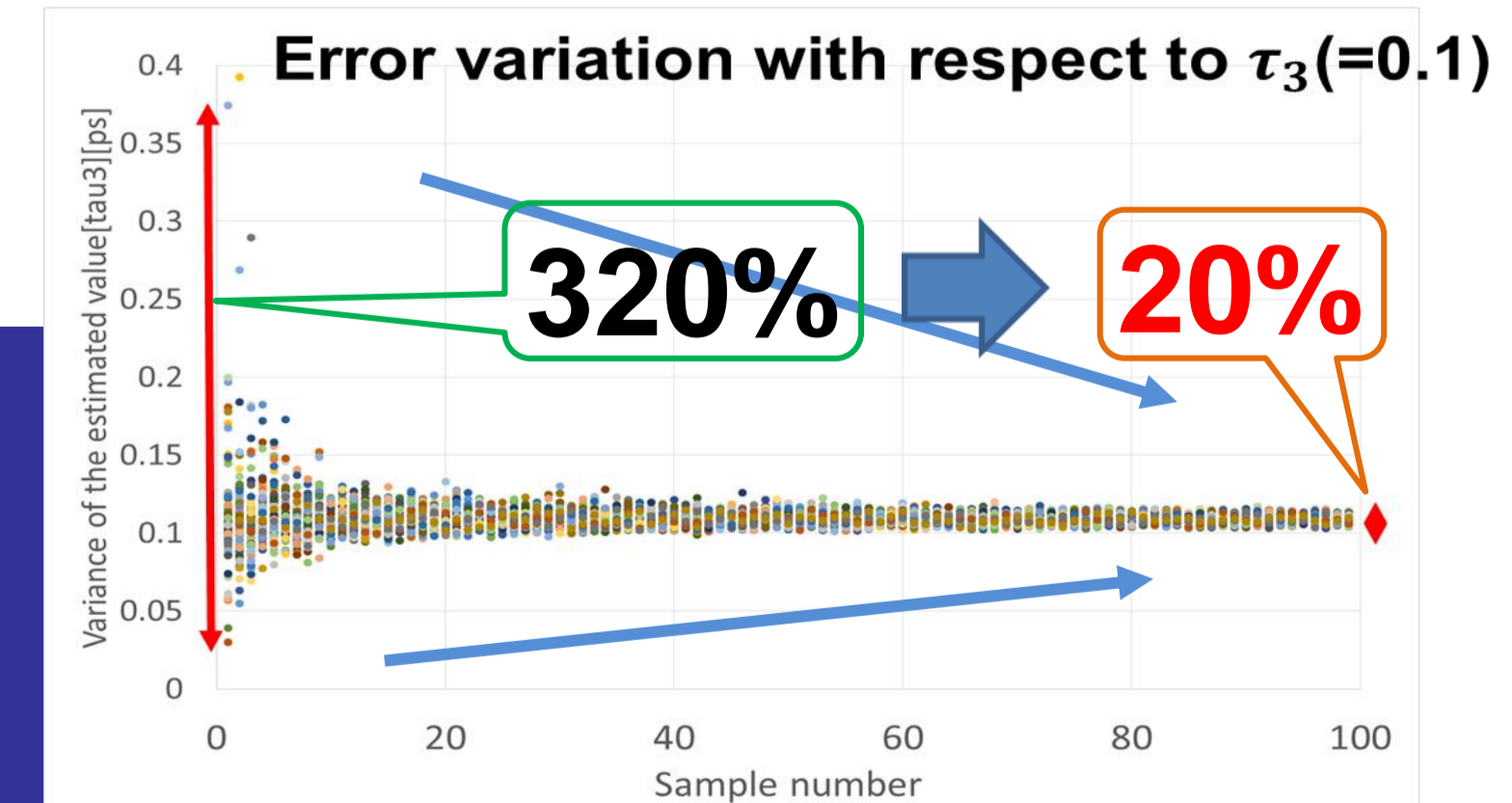
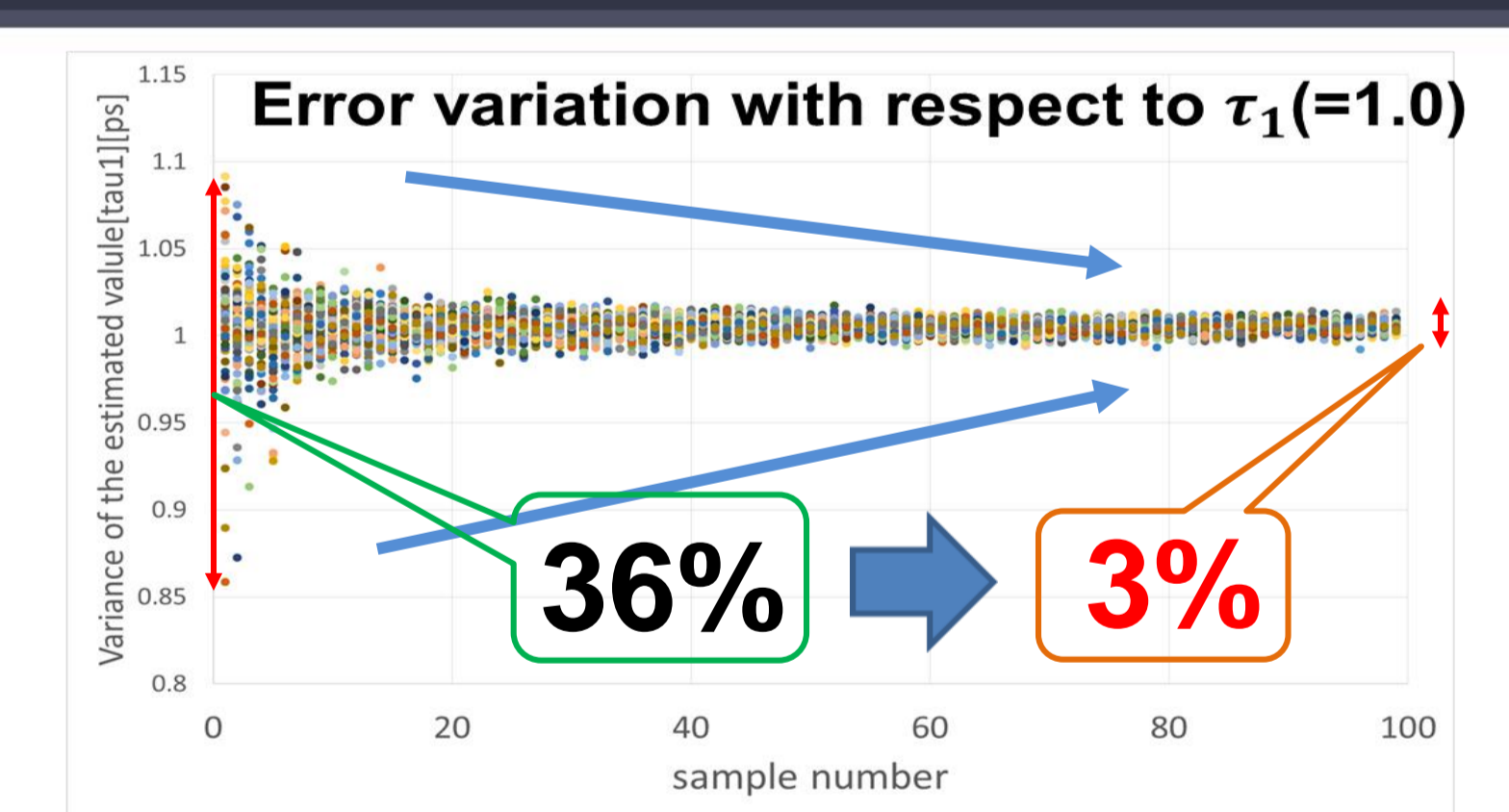
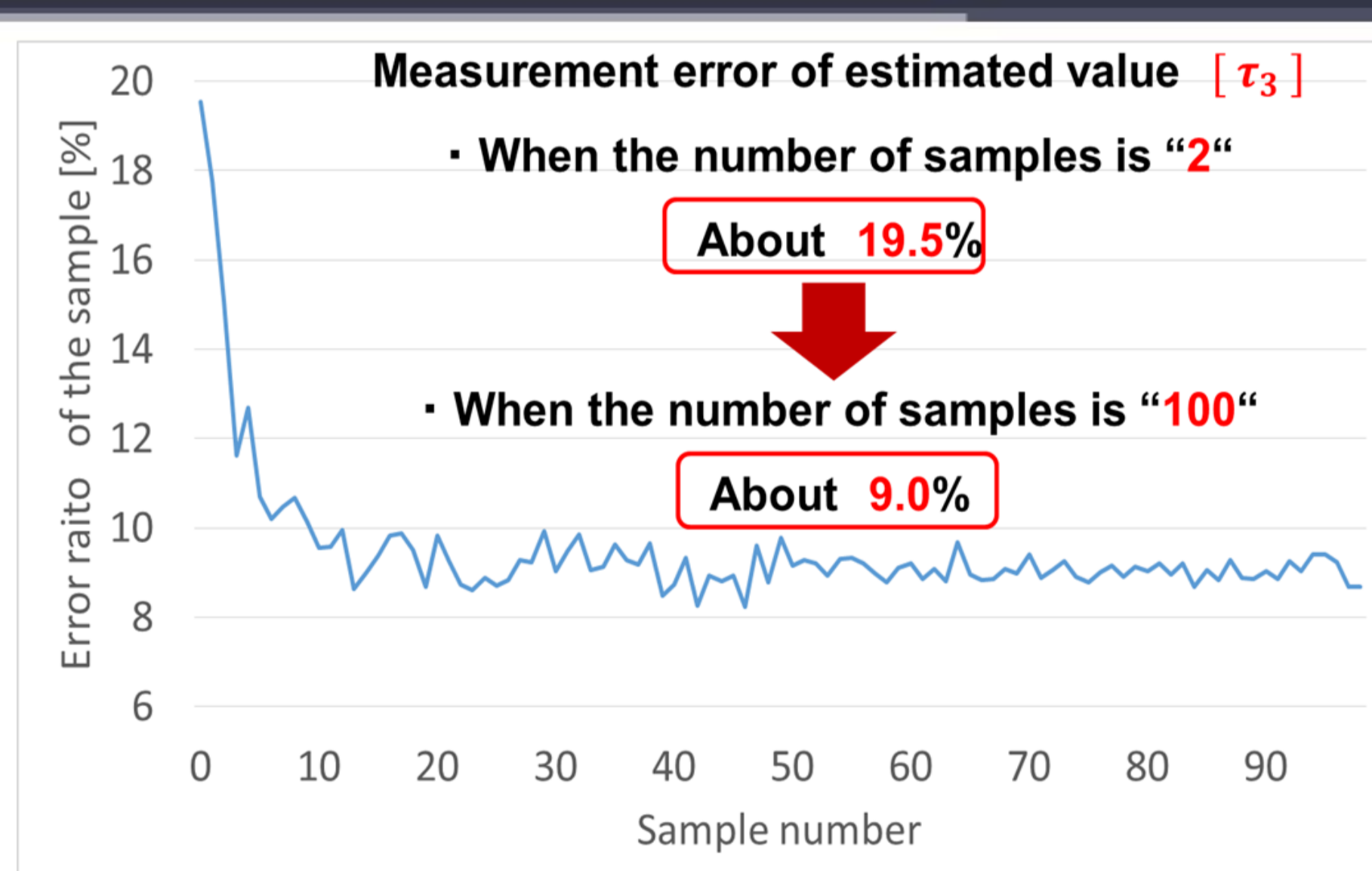
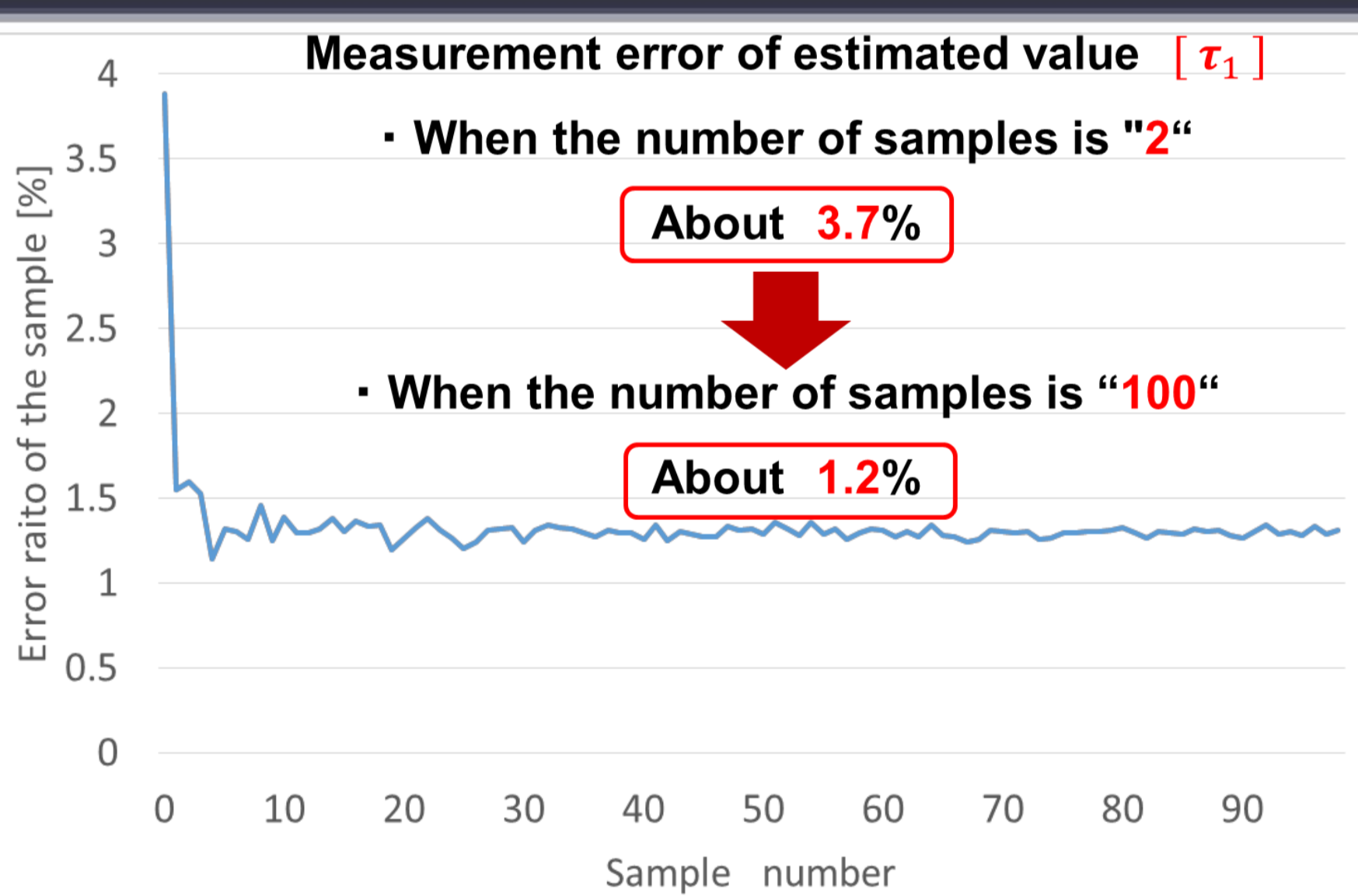
Explanation of the self-calibration algorithm



Estimate the delay value of the actual delay element by increasing the number of samples

Linear TDC

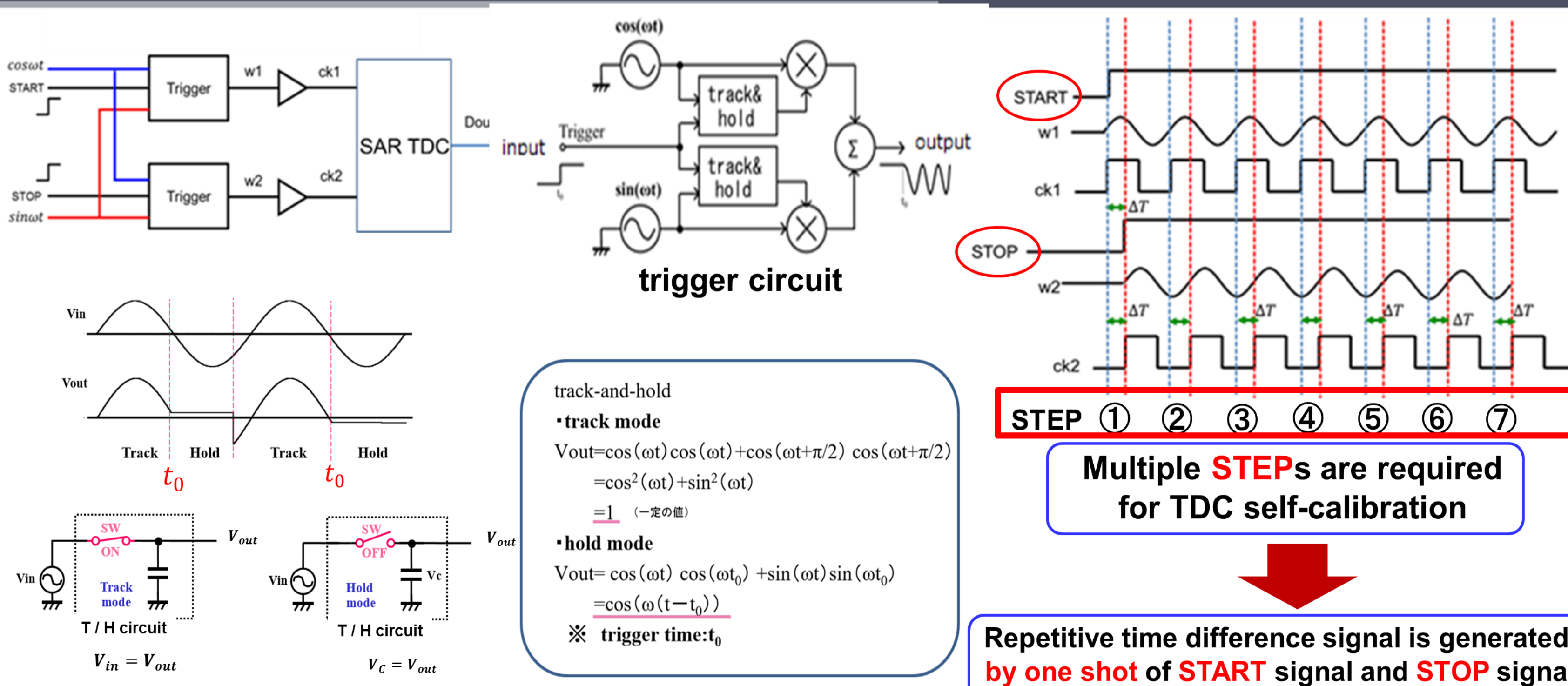
Simulation Result : Measurement error of estimated value



Increased reliability by increasing the number of samples
Sufficient reliability!

One-shot timing measurement

[III] Self-configuring circuit using trigger circuit



References

- [1] Y. Arai, T. Baba, "A CMOS Time to Digital Converter VLSI for High-Energy Physics", IEEE Symposium on VLSI Circuits (1988).
- [2] R. Jiang, C. Li, M. Yang, H. Kobayashi, et al., "Successive Approximation Time-to-Digital Converter with Vernier-level Resolution", IEEE IMSTW, Catalunya, Spain (July 2016).
- [3] Tektronics, Automatic RF Techniques Group 56th Measurement Conference - Metrology and Test for RF Telecommunications, Boulder, Colorado (Dec. 2000).